

<b>Notice of References Cited</b>	Application/Control No. 10/773,610		Applicant(s)/Patent Under Reexamination YAMANAKA ET AL.	
	Examiner Emmanuel Bayard		Art Unit 2611	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0161421	08-2003	Schmidt et al.	375/346
*	B	US-2005/0226341	10-2005	Sun et al.	375/260
*	C	US-7,746,925	06-2010	Hsu et al.	375/233
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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